Appl. No. 10/711,556
Amdt. dated 05/24/2005
Reply to Office action of 02/24/05

Amendments to the Specification:

page 4, last paragraph

These prior-art PFA techniques (e.g., COLE305, COLE183, KOYAMA) tend to be good at detecting and isolating "hard" static failures such as "Shorts: {Low electrical Resistance} or "Opens: {High Electrical Resistance} in devices) but tend not to be useful for detecting and isolate "AC" type critical parameter failure mechanisms.. (e.g., timing sensitive failures, defects that cause only Vmin or Vmax failures, timing or voltage condition sensitive failures, etc.).

replace with

These prior-art PFA techniques (e.g., COLE305, COLE183, KOYAMA) tend to be good at detecting and isolating "hard" static failures such as "Shorts: (Low electrical Resistance) or "Opens: (High Electrical Resistance) in devices but tend not to be useful for detecting and isolating "AC" type critical parameter failure mechanisms (e.g., timing sensitive failures, defects that cause only Vmin or Vmax failures, timing or voltage condition sensitive failures, etc.).